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FORM PTO-1449

U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE ATTY. DOCKET NO. MICRON. 3DV2C1 APPLICATION NO. Unknown

INFORMATION DISCLOSURE STATEMENT BY APPLICANT

APPLICANT **SCHUEGRAF**

(USE SEVERAL SHEETS IF NECESSARY)

FILING DATE GROUP Herewith

Unknown

U.S. PATENT DOCUMENTS							
EXAMINER DOCUMENT NUMBER INITIAL		DATE	DATE NAME		SUBCLASS	FILING DATE (IF APPROPRIATE)	
Sul	5,043,780	08/27/91	Fazan et al.				
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*EXAMINER: INITIAL IF CITATION CONSIDERED, WHETHER OR NOT CITATION IS IN CONFORMANCE WITH MPEP 609; DRAW LINE THROUGH CITATION IF NOT IN CONFORMANCE AND NOT CONSIDERED, INCLUDE COPY OF THIS FORM WITH NEXT COMMUNICATION TO APPLICANT.

			FOREIGN PATENT DOCUMENTS				_
EXAMINER	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
INITIAL						YES	NO
Ms	403136361	06/11/91	Japan	257	306		
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EXAMINER INITIAL	OTHER DOCUMENTS (INCLUDING AUTHOR, TITLE, DATE, PERTINENT PAGES, ETC.)
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